

Qualification Results Summary for ADuM5210/ADuM5211/ADuM5212 Die Revision, and Data Sheet Change

QUALIFICATION PLAN / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	3x77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	3x77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3x77	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	3x77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	1x77	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	1x30	Pass
Latch-Up	JEDEC <i>JESD78</i>	1x9	Pass ±200mA @ +8.25V
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	3/voltage	Pass ±4000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass ±1250V

*Preconditioned per JEDEC/IPC J-STD-020

Current Data Sheet Limits				
ADuM5210, ADuM5211, ADuM5212				
5V Operation (From:)				
Specification	Min	Typ	Max	Unit
Propagation Delay (C grade only)	13	18	24	ns
VISO Setpoint	x	5.0	x	V

3.3V Operation (From:)				
Specification	Min	Typ	Max	Unit
Propagation Delay (C grade only)	20	25	33	ns
VISO Setpoint	x	3.3	x	V

Mixed 5V/3.3V Operation (From:)				
Specification	Min	Typ	Max	Unit
Propagation Delay (C grade only)	13	20	26	ns
VISO Setpoint	x	3.3	x	V

Revised Data Sheet Limits				
ADuM5210, ADuM5211, ADuM5212				
5V Operation (To:)				
Specification	Min	Typ	Max	Unit
Propagation Delay (C grade only)	20	23	29	ns
VISO Setpoint	4.675	5.0	5.325	V

3.3V Operation (To:)				
Specification	Min	Typ	Max	Unit
Propagation Delay (C grade only)	22	27	35	ns
VISO Setpoint	3.135	3.3	3.51	V

Mixed 5V/3.3V Operation (To:)				
Specification	Min	Typ	Max	Unit
Propagation Delay (C grade only)	20	25	31	ns
VISO Setpoint	3.135	3.3	3.51	V